S	arch	Notes	
			Ш
	U SILLE ILLE	I URIR RIKKI IRUR WI I	III

Application/C ntr I No.	Applicant(s)/Patent und R examinati n	der
10/521,683	SCHMIDT ET AL.	
Examiner	Art Unit	
Hai H. Huvnh	3747	

SEARCHED			
Class	Subclass	Date	Examiner
123	598	5/23/2006	ннн
123	599	5/23/2006	ннн
123	601	5/23/2006	ннн
123	605-606	5/23/2006	ннн
123	608	5/23/2006	ннн
123	143B	5/23/2006	ннн
123	634	5/23/2006	ннн
333	246-248	5/23/2006	ннн
333	99PL	5/23/2006	ннн

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
		•	
			1

(INCLUDING	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR		
East .	5/23/20	06 ННН		